Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	ler	
10/724,172	TAKEYAMA ET AL.		
Examiner	Art Unit		
TUYEN T. NGUYEN	2832		

SEARCHED					
Class	Subclass	Date	Examiner		
336	90-96, 107, 192, 198	5/13/2005	TTN		
123	634-635	5/13/2005	TTN		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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